

PA200/AP200-BlueRay

Fastest production testing without compromising accuracy

Operation lamp for machine status

Instrument shelf for easy access to measurement equipment

Universal platen setup

- For use with DC and RF positioners and probe cards

Base machine

- 200 mm x/y stage for reliable 24/7 operations
- Low maintenance
- Designed for fast die stepping up to 10 die/sec
- High-accurate Z-stage for minimum scrub mark

Chuck

- Conductive chuck surface with vacuum holes for thin wafers
- Integrated AUX sites for calibration and cleaning sites
- Thermal test capability (25° C to 150° C)

Integrated vibration isolation system

- Eliminates vibration from external sources (acoustic, architectural, etc.)
- Enhances system stability
- Reduces damage to pads, wafers and probe tips

Powerful ProberBench™ operating environment

- Stable, Linux-based controller
- Real time PID motion controller
- Z-Profling: Automatic wafer warpage compensation
- Integrated, reliable industrial PC for running ProberBench software

Small footprint machine table

- Integrates all prober components and supplies
- Integrated rollers

Engineering prober screen

- Operate machine in a semi-automatic engineering mode
- Free die-to-die navigation on wafer
- Individual die testing

Advanced software automation tools

- PACE - Easy to use control environment for production testing
- Powerful pattern recognition software
- Including a flexible interface for tester integration

Microscope

- High-resolution optics for probe inspection, wafer navigation and alignment

Expert control panel

- Comfortable use without PC
- Full control of all probe stages with position feedback
- Entire system control from one panel
- Analog joystick for precise, sub-micron positioning
- Point-and-shoot navigation

Loader module

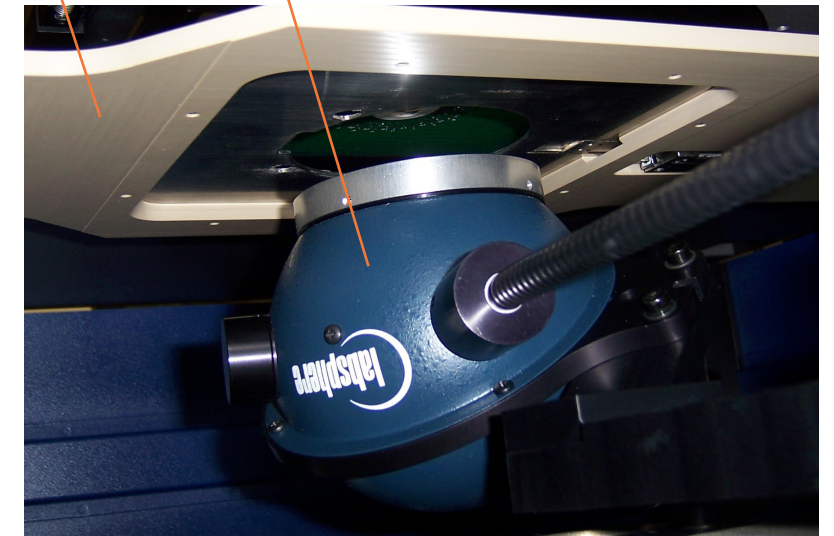
- Universal cassette stand for substrates from 2" to 8"
- Integrated pre-aligner for flat/notch detection
- Barcode/2D Matrix code/OCR wafer code recognition
- Field upgradeable

PA200 DS BlueRay

Chuck for double-sided substrates

Measurement instrumentation

- Prepared for 4" integrating sphere, fiber optics



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PA/AP200R-PH-0911

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